

| Ref # | Hits | Search Query  | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|---|---|------------------|---------|------------------|
| L1    | 66   | ((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))              | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:08 |
| L2    | 0    | ((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))same pattrens | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:08 |
| L3    | 0    | ((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))same pattren  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:08 |
| L4    | 0    | ((wafer\$1 or semiconductor\$1 or chip\$1 or substrate\$1)with(repetit\$3 and non-repetit\$3))with pattren  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:08 |
| L5    | 11   | 1 and (cell or array or matrix)with(contrast or threshold)  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:22 |
| L6    | 11   | 1 and 5 and (detect\$3 or defects or fault or flaw)   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:11 |
| L7    | 4    | 6 and (cell or array or matrix)with(1D or one adj dimensional\$1)   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:23 |
| L8    | 1    | 7 and @ad<"20011024"  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/10 09:24 |